

Automated Multi-Device Test Process and System

Abstract

A method, system and software for automatically generating a test environment for testing a plurality of devices (DUTs) under test in a test system. The multiple devices are tested by mapping the plurality of DUTs into pins of the tester system to create pin data; inputting into a test program generator pattern data, generic test program rules and the pin data; generating a multi-DUT test program and multi-DUT pattern data; and controlling the test system through the test program. The resulting fail data is then logged to each DUT.